

<b>Notice of References Cited</b>	Application/Control No. 10/684,074	Applicant(s)/Patent Under Reexamination EFSTATHIOU, JOHN D.	
	Examiner Anthony Weier	Art Unit 1761	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,348,230	02-2002	Campbell et al.	426/614
	B	US-4,877,625	10-1989	Dieu et al.	426/250
	C	US-6,162,441	12-2000	Chae et al.	424/241.1
	D	US-2,476,412	07-1949	HARRIS BENJAMIN R	426/47
	E	US-3,656,534	04-1972	Bain et al.	426/614
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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